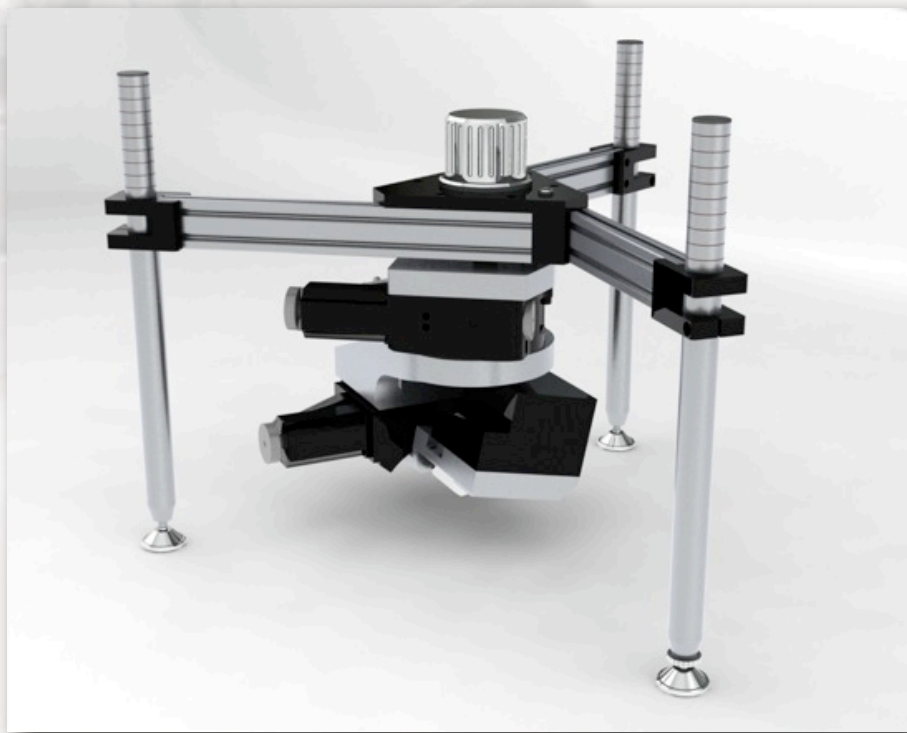




T N X



Enixe

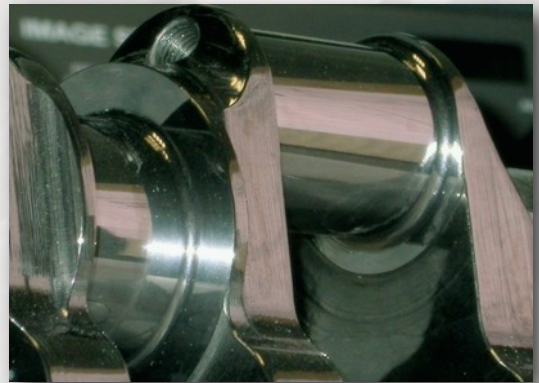
Residual Stress Portable Diffractometer

A New Challenge in X-Ray Diffraction

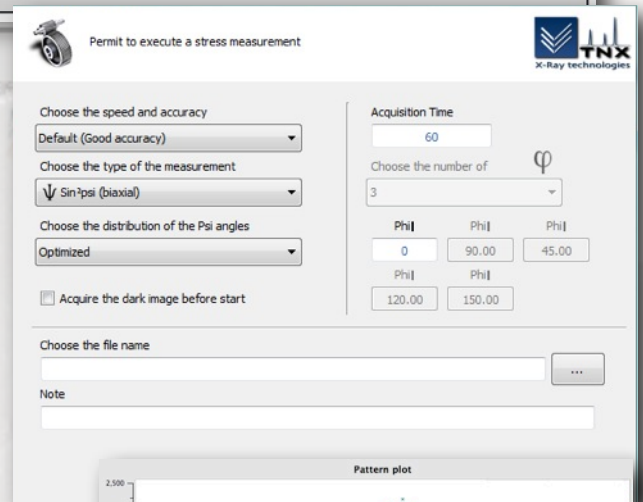
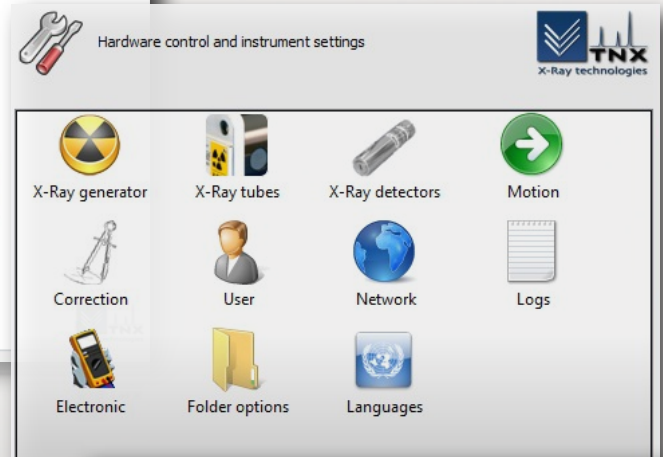
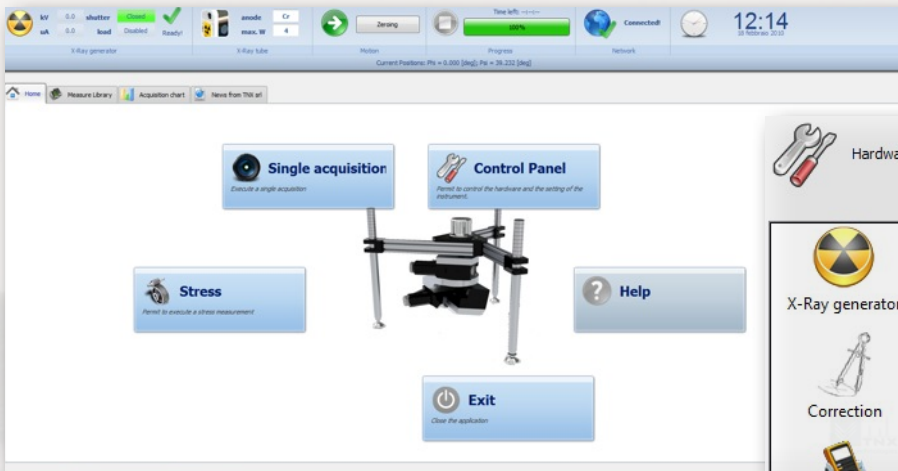


Main Applications

- shot peening (*connecting rods, gears, turbine blades, pinions, driving shafts, springs...*)
- thermal treatment
- fatigue damage analysis
- welding
- lapping
- coating
- forging



Portable ENIXE: suitable for unlimited dimensions!

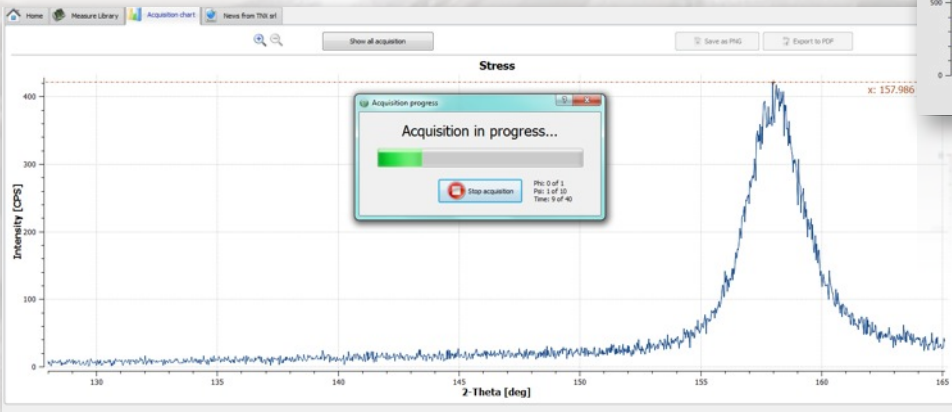
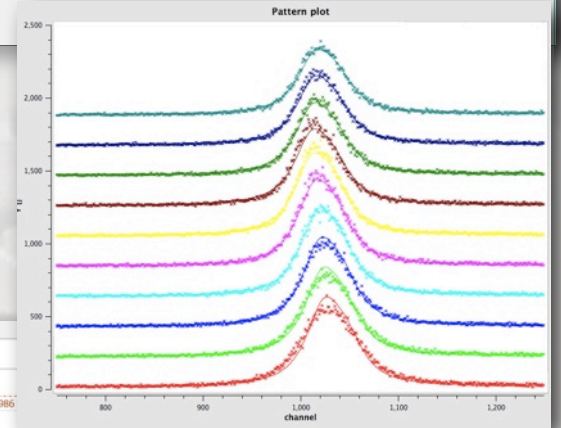


NYX (ΝΥΞ): data collection software



XENIA (Ξένια): data analysis software

- Full-profile approach by using the Rietveld method
- Accuracy and flexibility assurance
- Application on wide variety of Materials
- Critical microstructures and phase combinations control



```

Plane stress refinement for Sample:
-----
phase:
sigma phi (MPa) = -1029.16
sigma sum (MPa) = -2661.31
-----
R factor: 0.111327
weighted R factor: 0.130827
experimental R factor: 0.0312616
goodness of fit: 4.18491
    
```

XENIA and NYX operating under any tool platform (Windows, Mac OSX, Linux)

Data Sheet

X-Ray Tube	CrK α anode, 4 W power
Ψ Range	from -45° a +45°
Φ Range	from 0° a 360°
Detector	solid state detector 1280 active pixel 24x24 μ m each 64x8 mm area
Alignment	laser controlled
Analysis	biaxial, stress tensor retained austenite
Filter	Vanadium
Collimators	0.5 mm, 1 mm, 2 mm



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